

Si-DIODE/Gd DETECTORS FOR THERMAL NEUTRONS

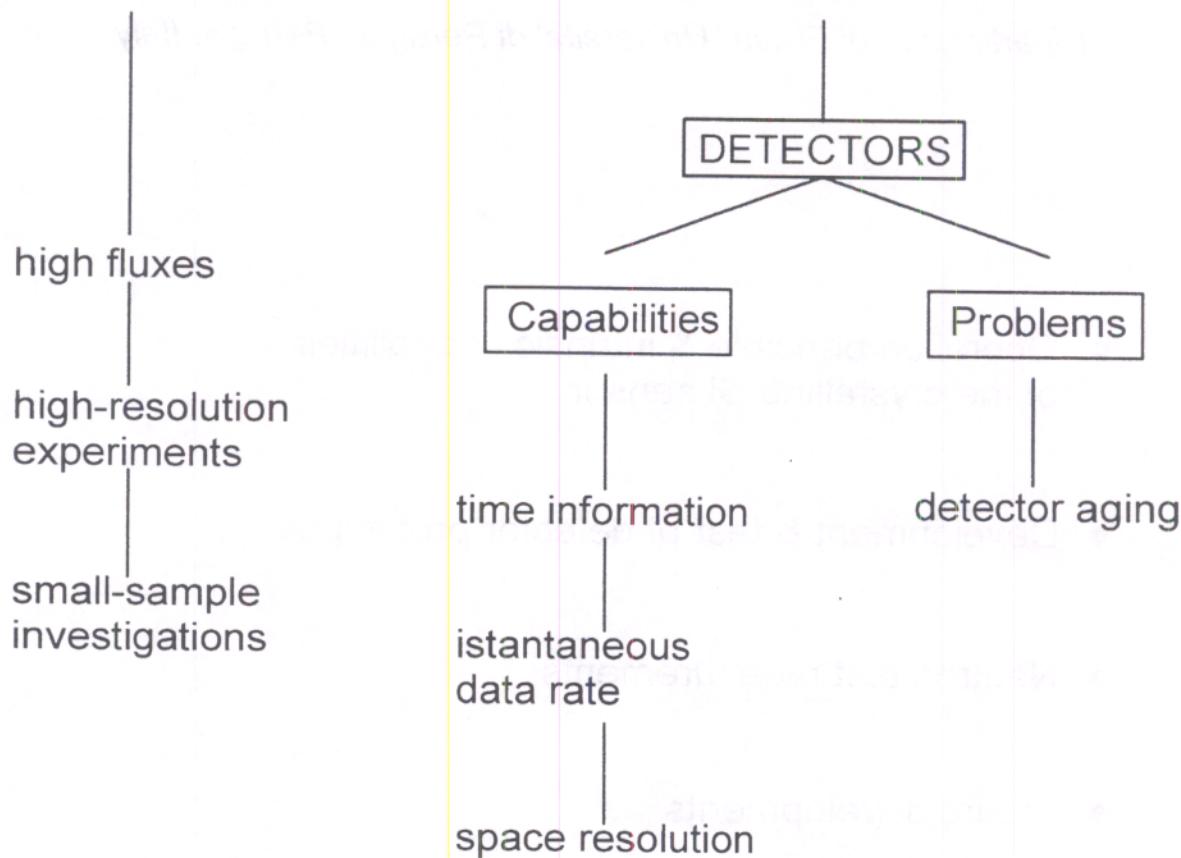
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- Operation principle & intrinsic capabilities of the crystalline Si sensor
- Development & test of detector prototypes
- Neutron test measurements
- Future developments

Research program developed under the E.U. Project XENNI

NEXT GENERATION PULSED NEUTRON SOURCES



CRYSTALLINE Si SENSORS ARE KNOWN
FOR THEIR UNRIVALLED SPACE RESOLUTION
AT HIGH COUNTING RATES
(HEP-Trackers)

Si SENSOR coupled to VLSI READOUT ELECTRONICS

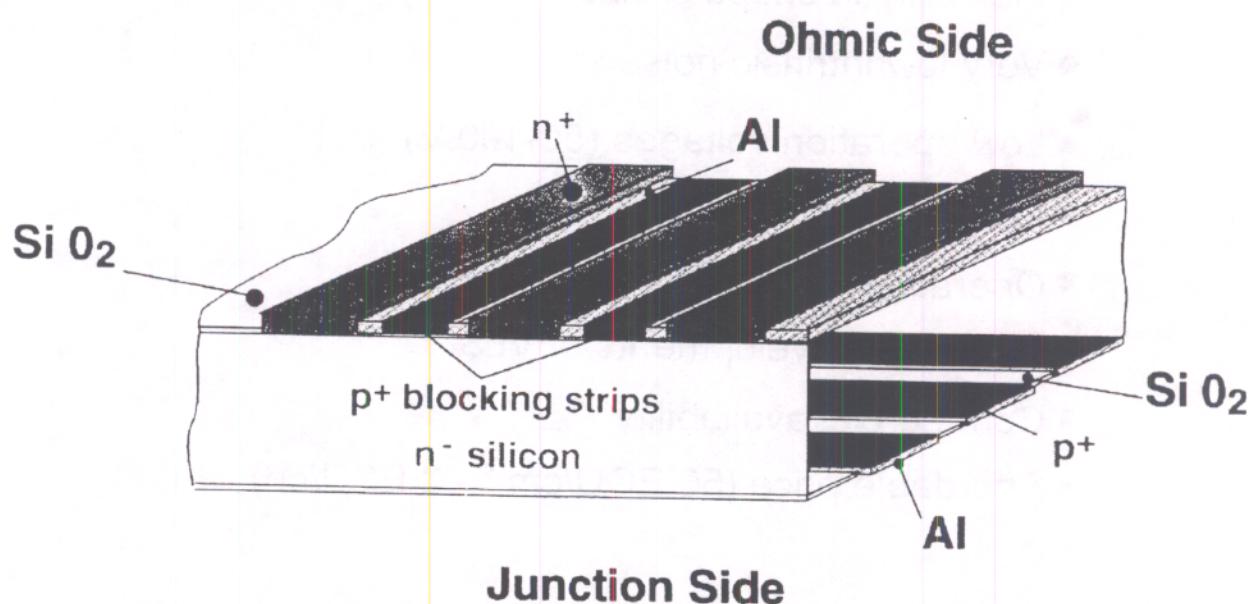
CAPABILITIES

- Count rates $> 10^6 \text{ s}^{-1}$
- Position resolution $< 50 \mu\text{m}$
- Flexibility in shape & size
- Very low intrinsic noise
- Low operation voltages (50-100 V)
- Low power VLSI
- Operation under vacuum possible
- Rad-hard developments of VLSI
- Commercial availability
- Affordable price ($50 \text{ ECU/cm}^2 - 2 \text{ ECU/ch}$)

AS NEUTRON DETECTORS/MONITORS

- Converter required → efficiency over a wide energy range
- γ -sensitivity (<1MeV)
- Radiation damage

The Double Side Silicon Wafer

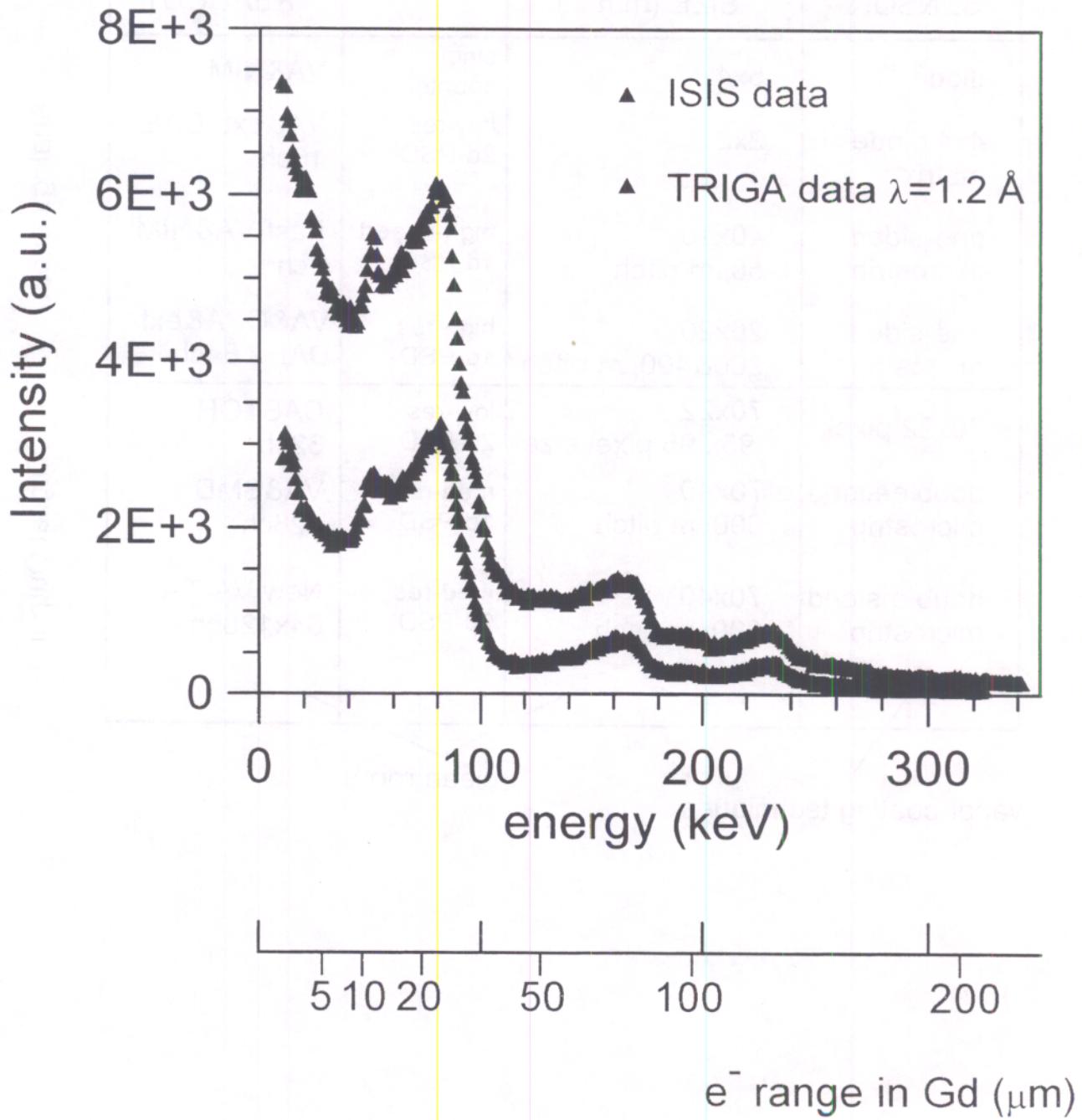


Schematic view of a double-sided silicon detector

Converter: natural Gd - $10\mu\text{m}$ & $250\mu\text{m}$ thick

$n + ^{155}\text{Gd} \rightarrow \text{Gd}^* \rightarrow \gamma\text{-spectrum}$

\rightarrow conversion e^- spectrum



PROTOTYPES DEVELOPED under XENNI

developed & tested

SENSOR	300 μm thickness SIZE (mm ²)		PARALLEL READOUT
diode	5x4	single counter	VA&NIM
4x4 diode matrix	2x2	low-res 2d-PSD	VA&ext. DAE 16ch
one-sided microstrip	40x10 50 μm pitch	high-speed 1d-PSD	Fast-VA&NIM 4ch
one-sided microstrip	20x20 200&400 μm pitch	high-res 1d-PSD	VA&OPA&ext. DAE - 64ch
70x22 pixel	70x22 .95x.95 pixel size	low-res 2d-PSD	CASTOR 32ch
double-sided microstrip	70x40 600 μm pitch	med-res 1d-PSD	VA&SMD 128ch
double-sided microstrip	70x40 600 μm pitch	med-res 2d-PSD	New VA-TA 64x128ch

vapor coating techniques

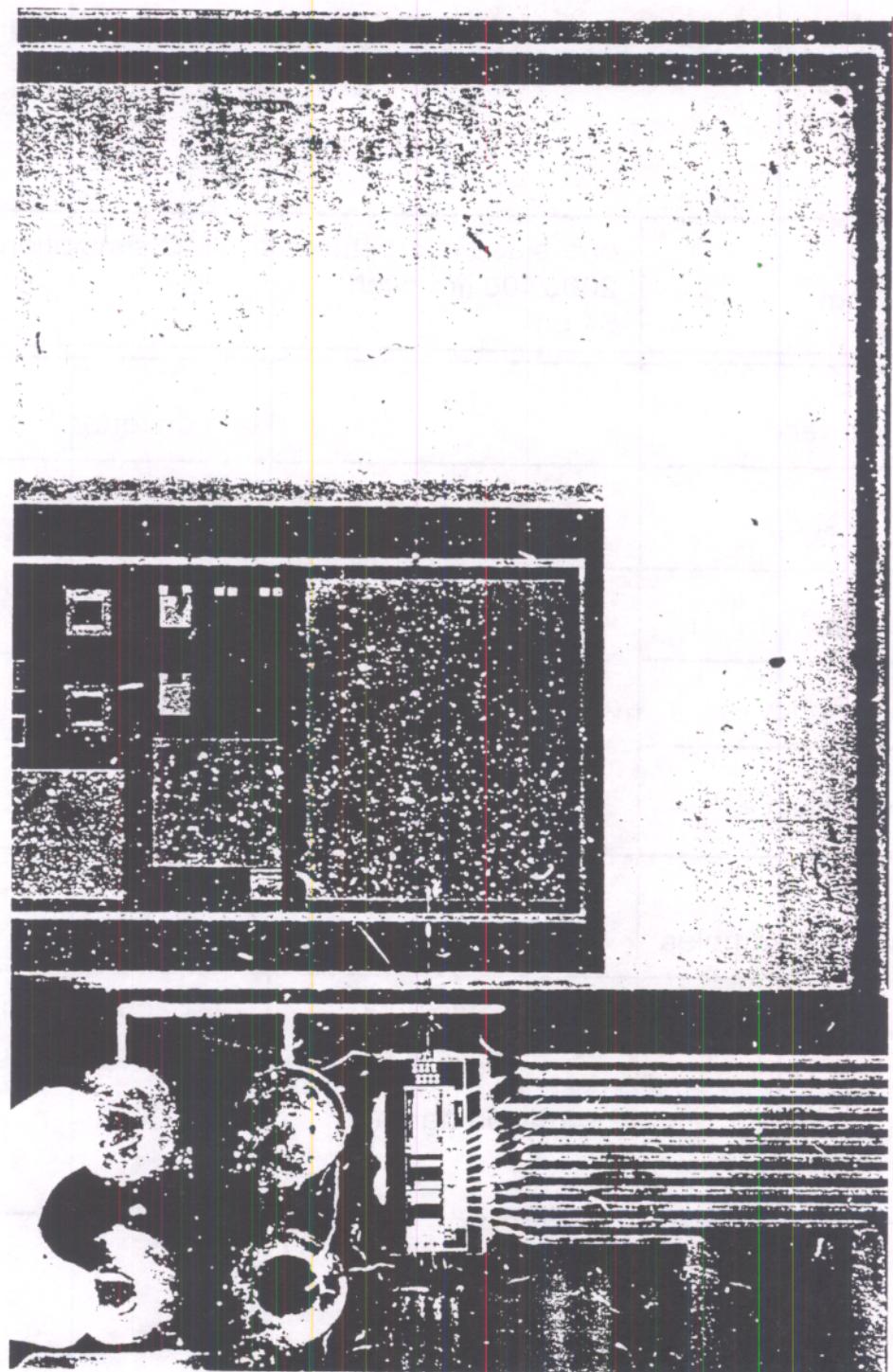
clean room

Analog Output

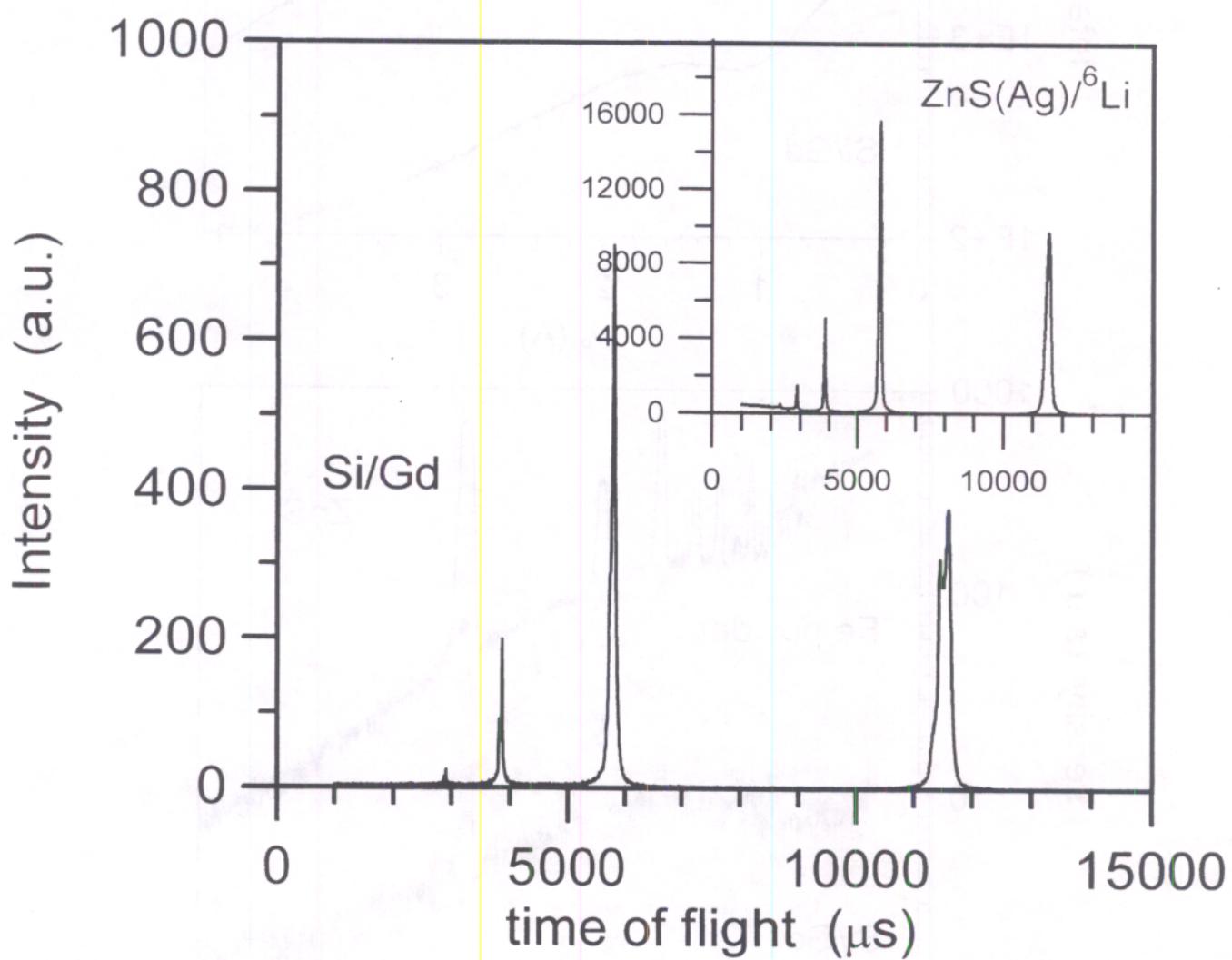
Digital Output

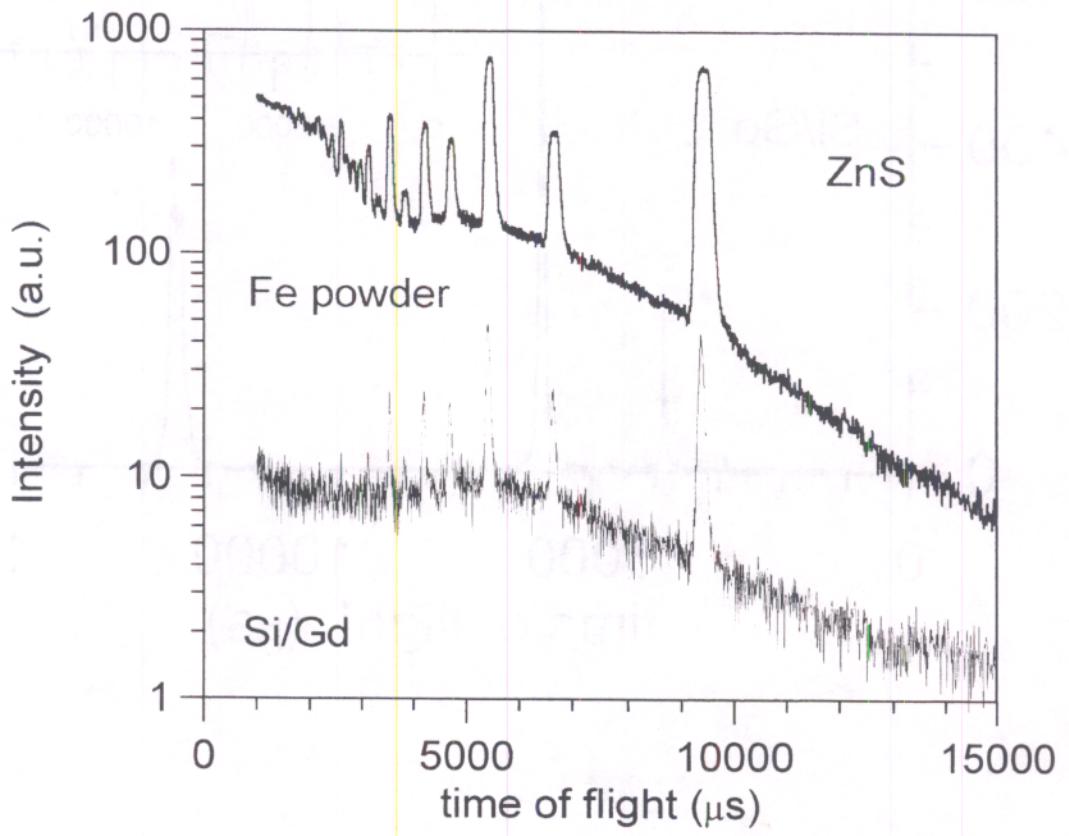
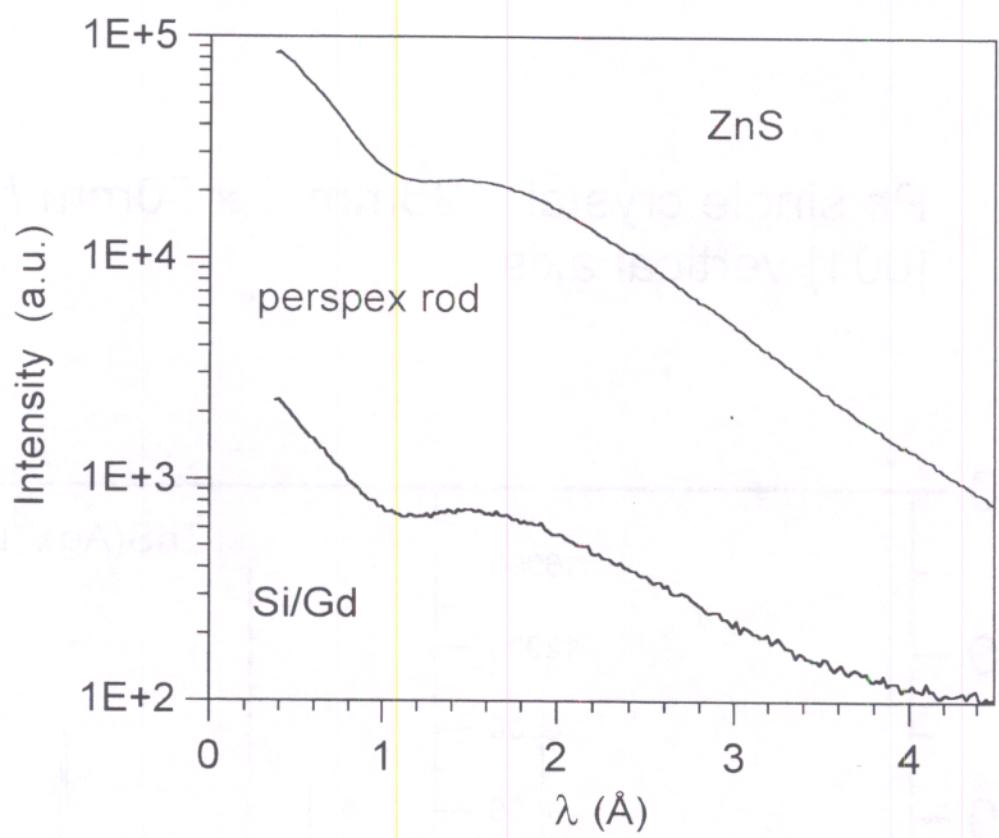
TEST MEASUREMENTS & MONTE CARLO SIMULATION

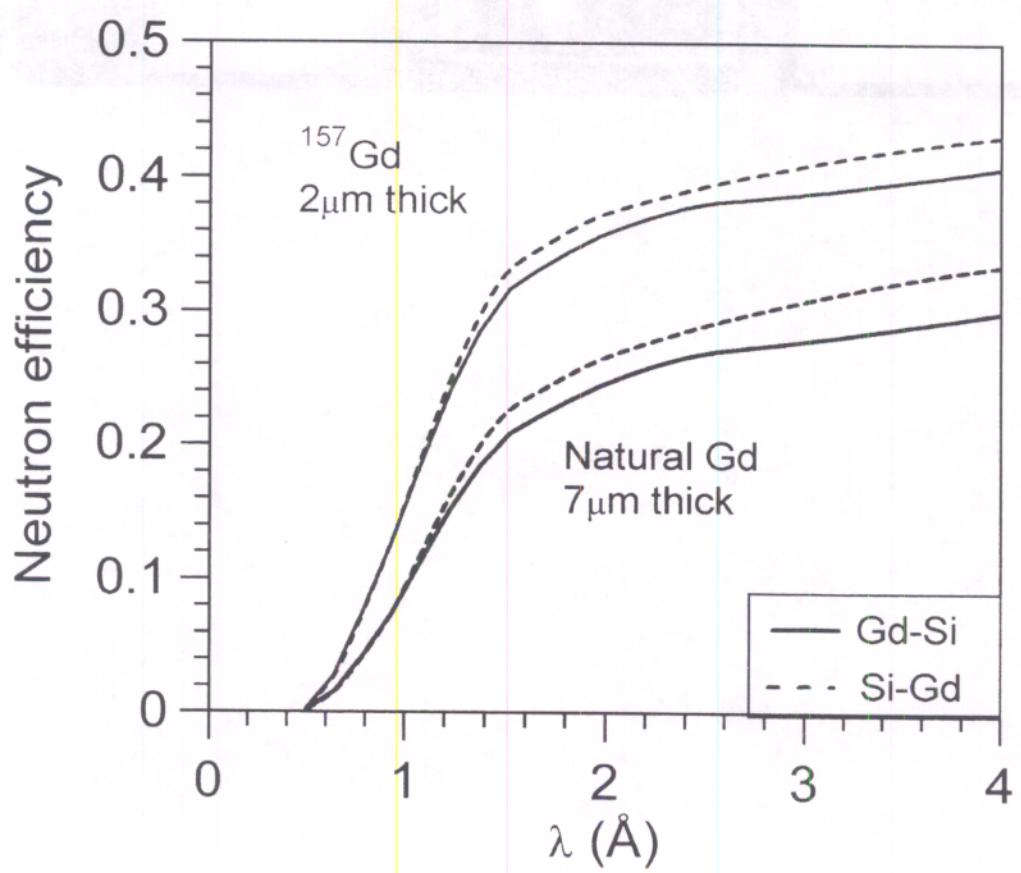
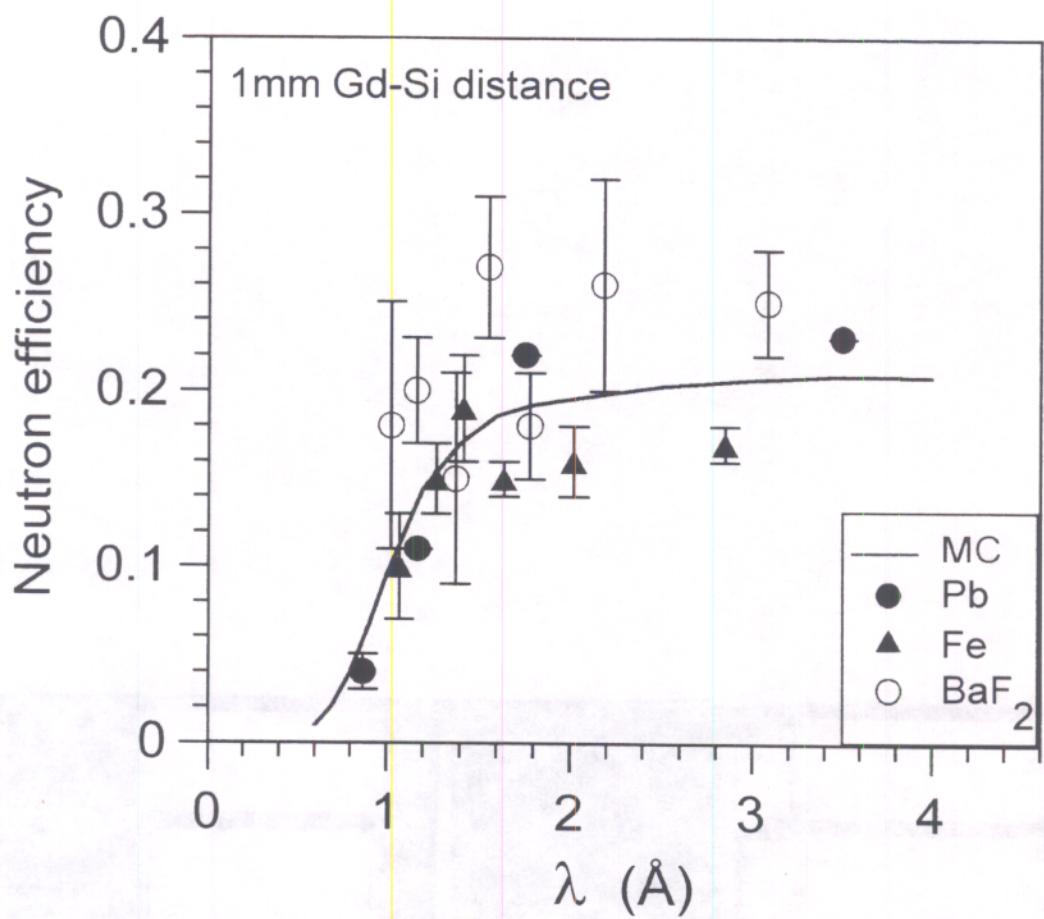
diode 5x4mm ²	one-sided microstrip 200&400 μm pitch 64 ch	MC simulation
converter		converter
pulse shape	pulse shape	
stability		
n-efficiency		n-efficiency
γ -sensitivity		γ -sensitivity
spectra of standard samples	small-size samples	
	space resolution	space resolution
	radiation damage	

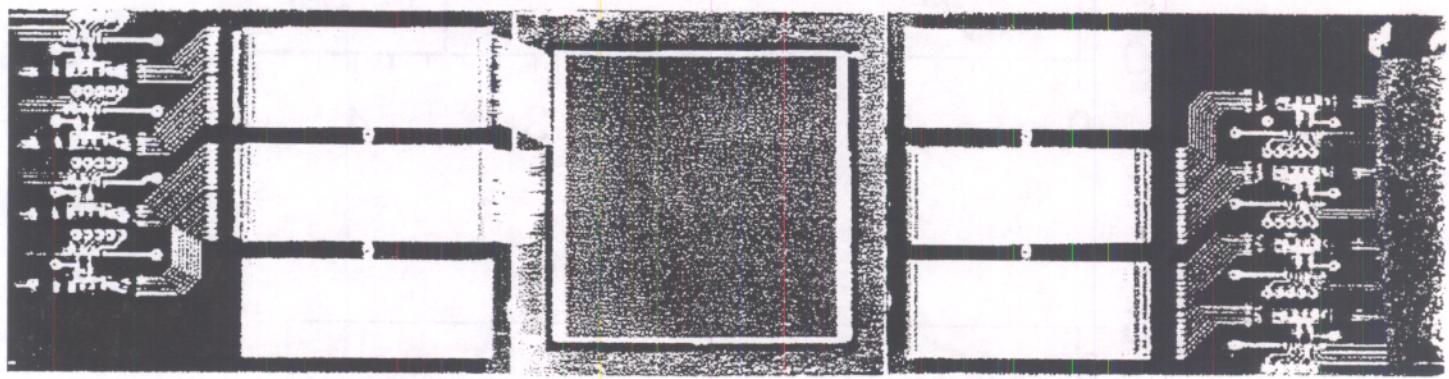


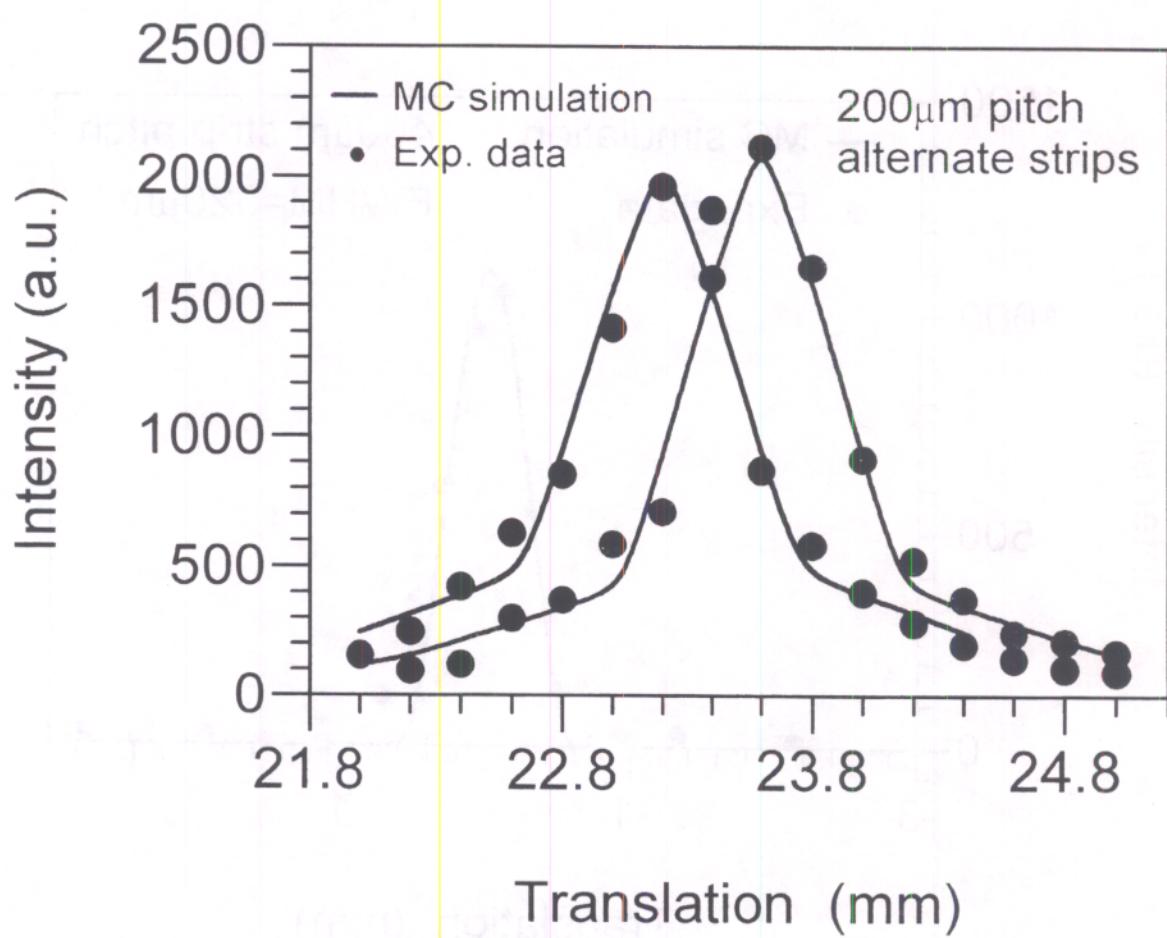
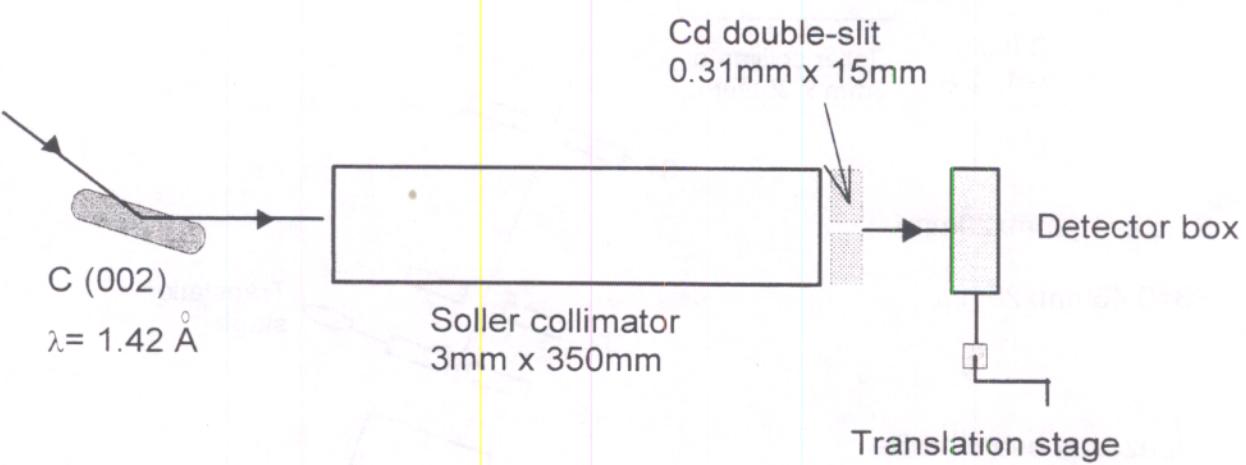
Pb single crystal - 25mm \times 50mm h
[001] vertical axis

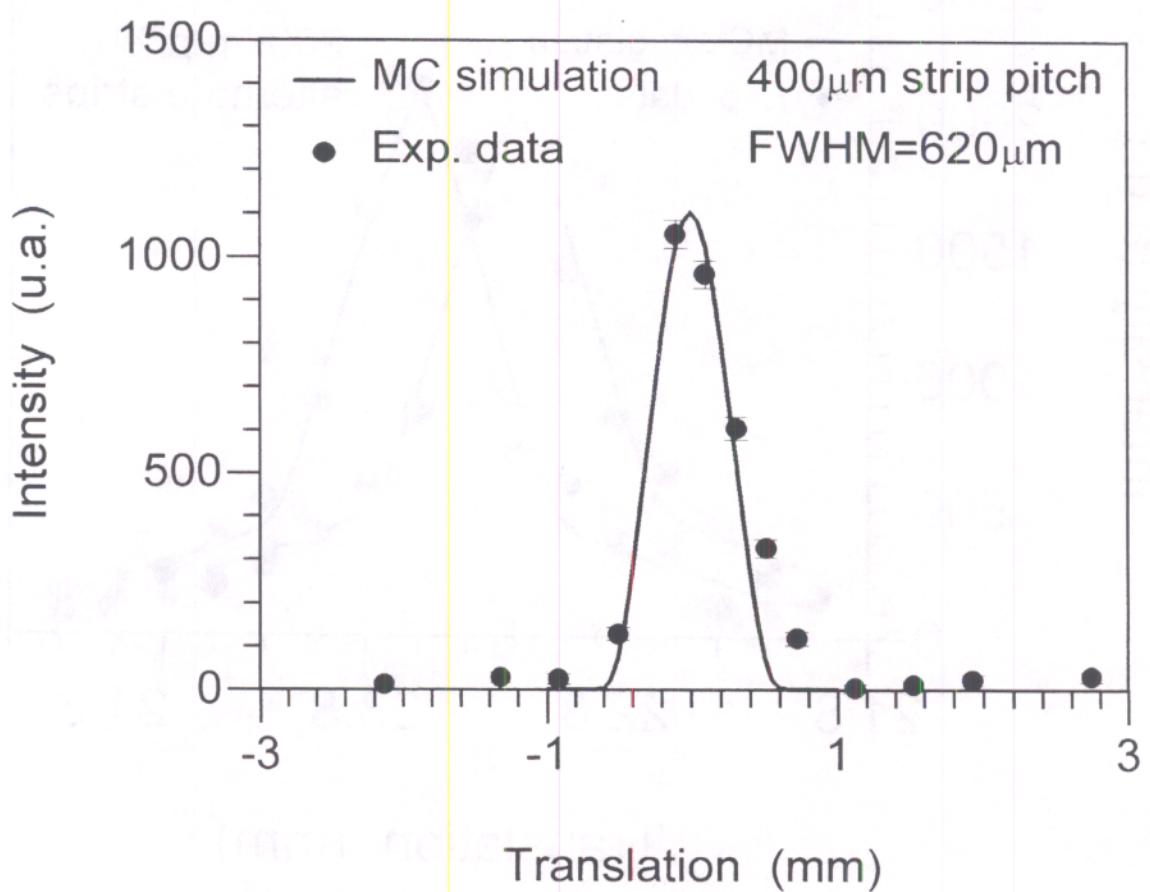
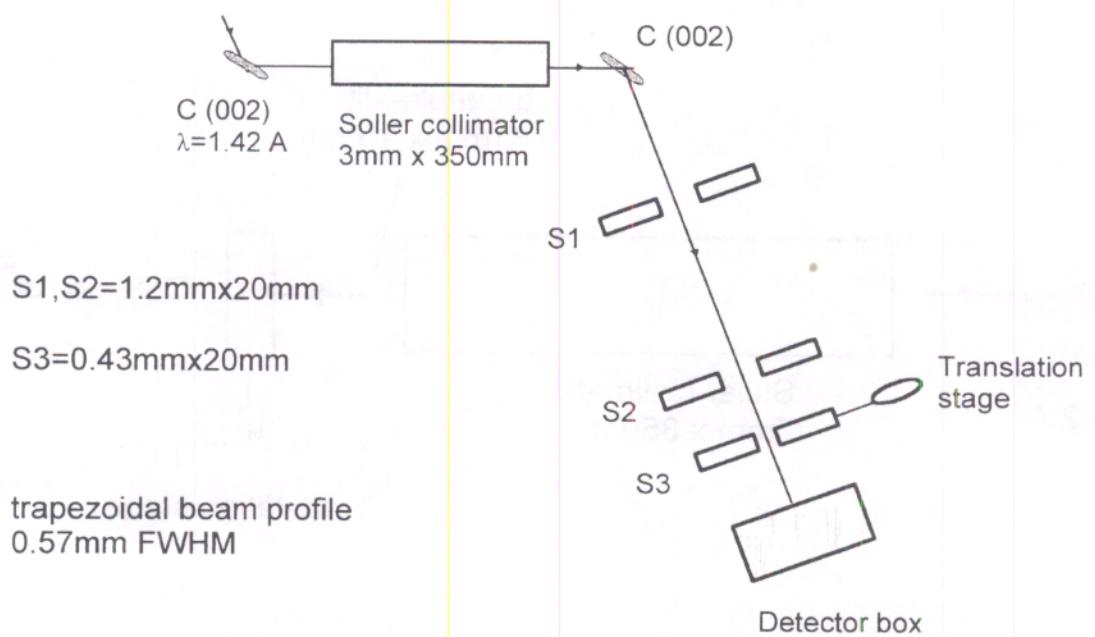


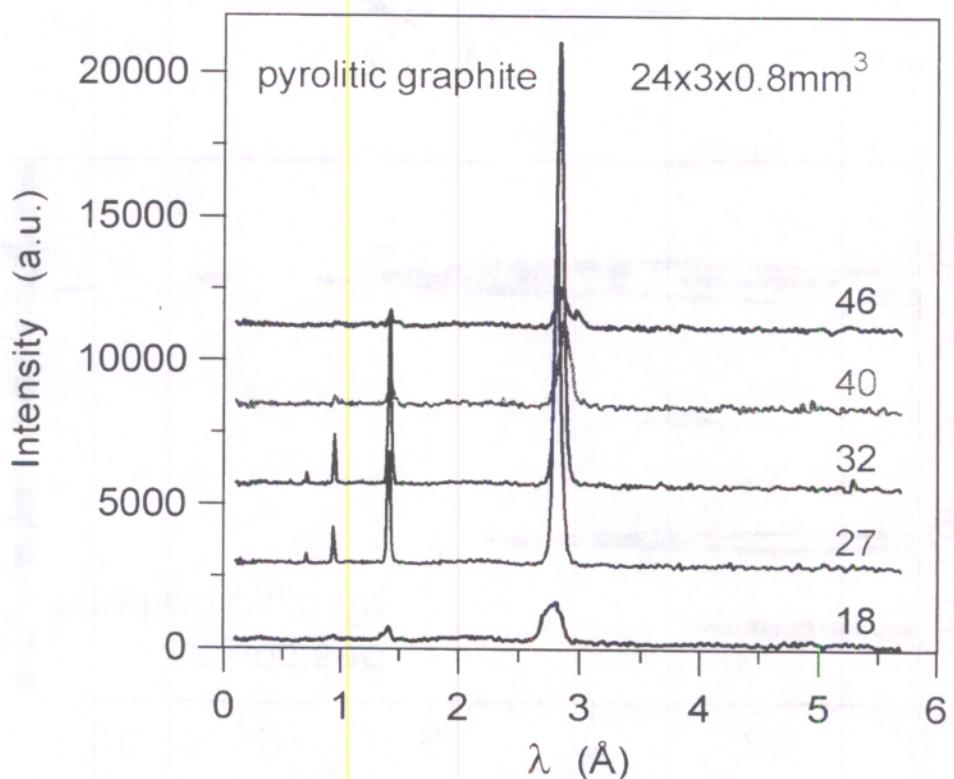




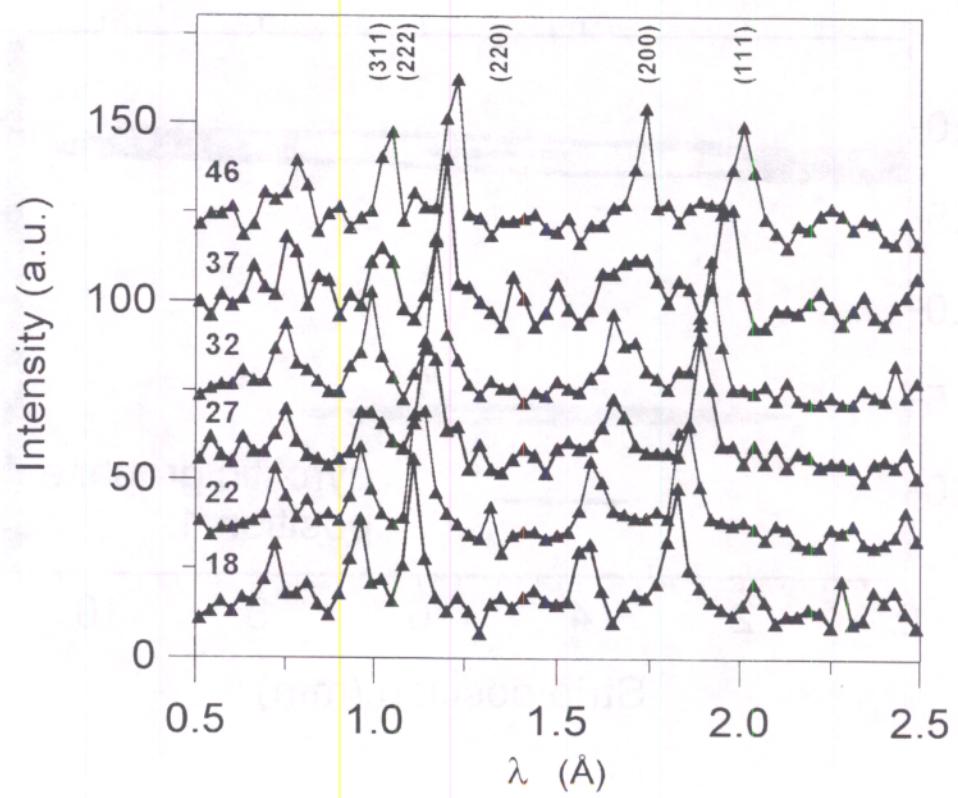


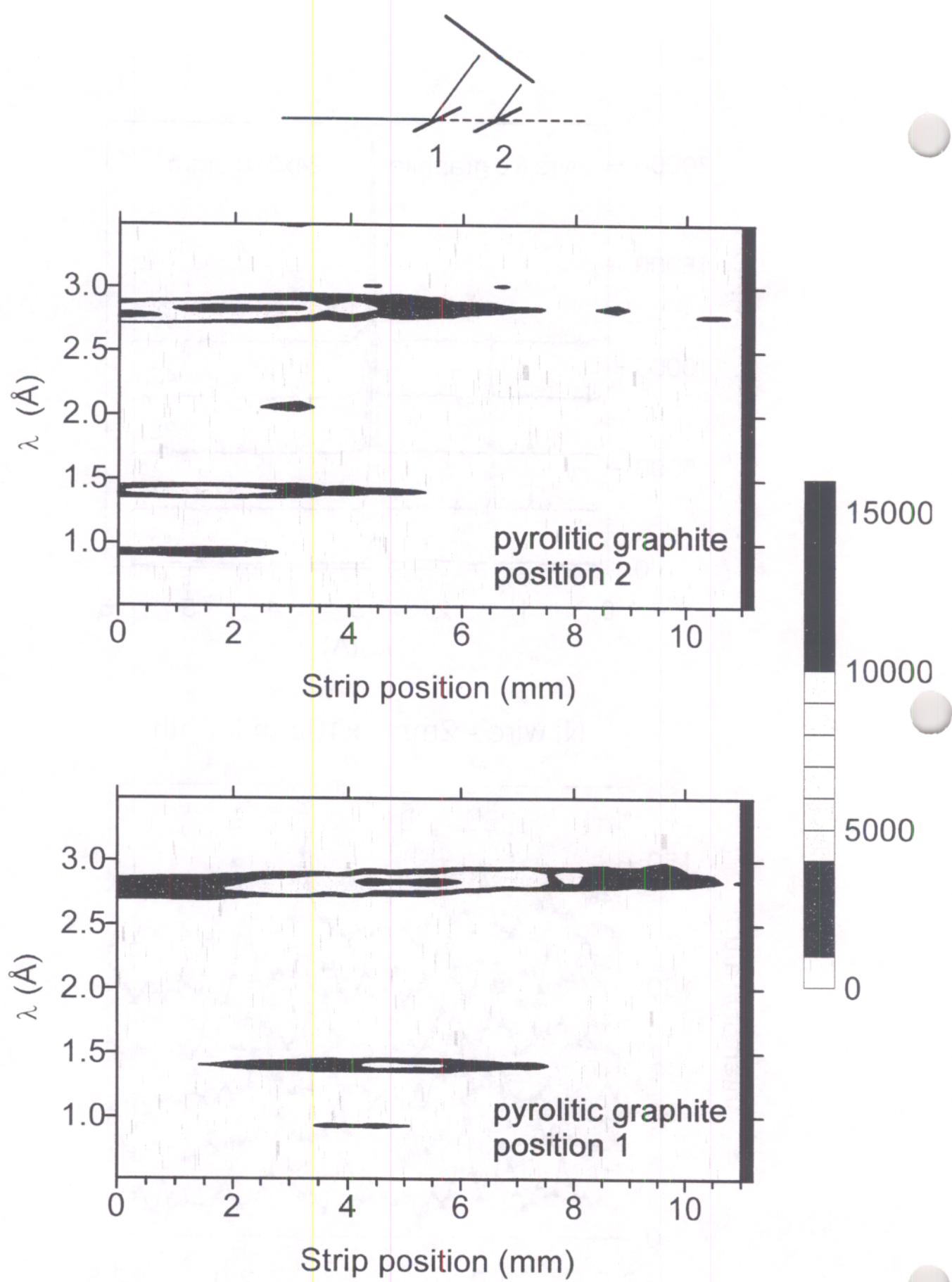




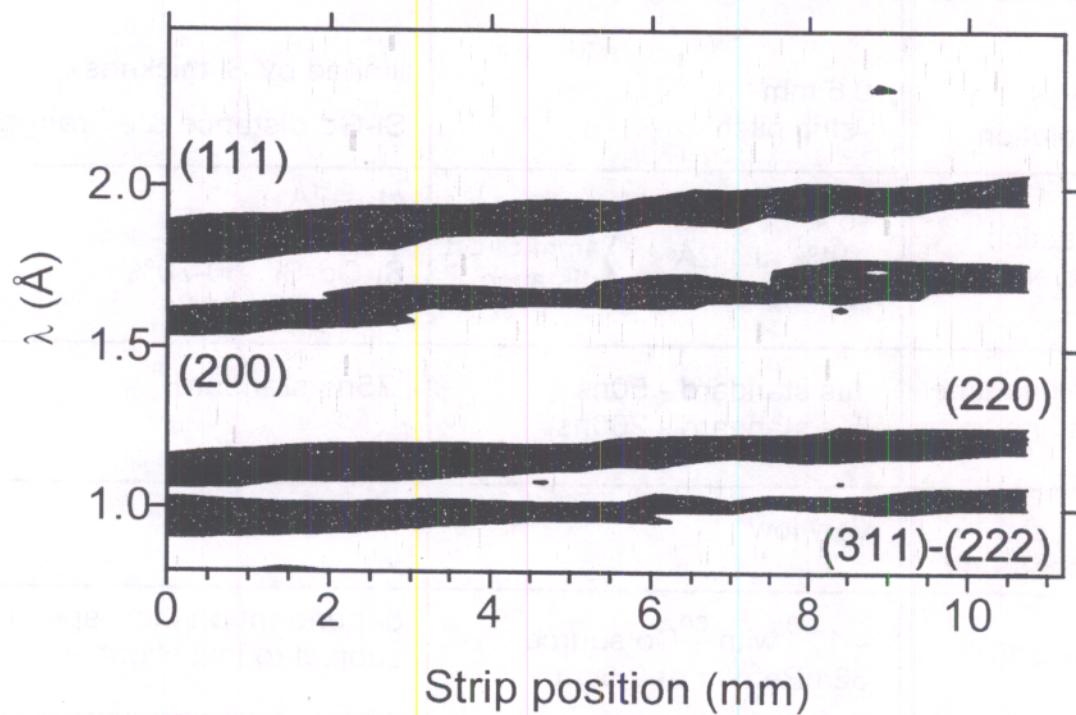


Ni wire - 2mm \times 10mm length





Ni wire



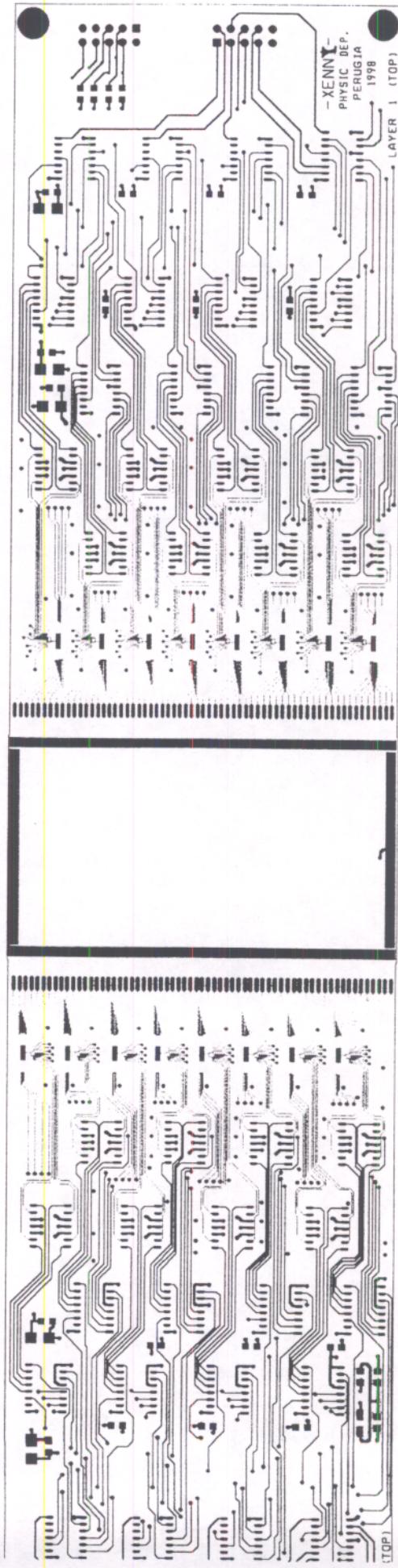
CRYSTALLINE Si DIODE/NATURAL Gd CONVERTER

	measured performance	achievable performance
space resolution	0.6 mm ~strip pitch	limited by Si thickness, Si-Gd distance & e ⁻ range
detection efficiency	~6% at 0.9Å ~14% at 1.2Å ~20% at 2Å	at $\lambda=2\text{\AA}$ Gd-Si 30% Si-Gd-Si 60-70% Gd-Si-Gd 50%
peaking time shaping time	1 μ s standard - 50ns 5 μ s standard - 200ns	75ns standard
intrinsic background	very low	
γ -sensitivity	$\sim 10^{-5}$ with ^{60}Co source 32mRem/hr at 2.5cm	dependent on the γ -spectrum subject to investigation
stability	excellent over 3 months continuous operation	dependent on radiation damage
radiation damage	$1 \times 10^{14} \text{ n/cm}^2$ & $2 \times 10^{14} \text{ n/cm}^2$ 2MeV neutron fluences -leakage current increase -type-inversion -depletion voltage increase	performances recovered by lowering sensor temperature (0°, -10°C) & increasing bias (LHC-collaboration)

- XENNI -

NEUTRON DETECTOR BOARD

1 LAYER TOP



ELECTRONIC SERVICE
INFN & PHYSIC DEP.
PERUGIA
(August 1998)

